

**Search Notes**

Application/Control No.

10/689,721

Examiner

ALEX LIEW

Applicant(s)/Patent under  
Reexamination

BAN ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/106,153,154 limited to text search	7/30/2008	AL